



#148 (1571081221): Study of Reliability of Electronic Systems at Low Temperature

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Paper title *Study of Reliability of Electronic Systems at Low Temperature* [✍](#)

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Abstract [📄](#) [✍](#) Operation of electronics materials, devices circuits and systems at low temperatures below -55oC...

Keywords Reliability; low temperature; electromigration; dielectric breakdown; negative bias; temperature instability [✍](#)

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